

Search Notes

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Examiner

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Applicant(s)/Patent under
Reexamination

YEN, CHIH-CHEN

Art Unit

3753

SEARCHED

Class	Subclass	Date	Examiner
137	544-550	6/21/2005	KL
251	40 120		
138	44, 45		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search	6/21/2005	KL